

**Search Notes**

Application/Control No.

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Examiner

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Applicant(s)/Patent under  
Reexamination

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Art Unit

2181

**SEARCHED**

Class	Subclass	Date	Examiner
710	5-7, 54, 310-311	10/23/2006	CS
711	137-151	10/23/2006	CS

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
710	6,54,310		

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PALM - DOUBLE PATENTING	10/23/2006	CS
EAST (USPGPUB, USPAT, USOCR, DPO, JPO, DERENT , IBMTDB)	10/23/2006	CS